

Search Notes



Application/Control No.

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Examiner

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**Applicant(s)/Patent under
Reexamination**

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114 of 114

2128

SEARCHED

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated East Search	2/20/2006	AS
Perfromed IEEE Seach (attached)	2/20/2006	AS
Consulted SPE	2/16/2006	AS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner